



Date: June 6, 2004

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FORM PTO 449 (Colb)	ATTY DOCKET NO. 4350-4004	SERIAL NUMBER 10/702,413
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Boris YOKHIN	EXAMINER (N/A)
	FILING DATE November 5, 2003	GROUP ART UNIT 2882

U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
CT	AA	5,740,226	Apr. 1998	Komiya, et al.	378	70	
	AB	5,619,548	Apr. 1997	Koppel	378	70	
	AC	5,923,720	Jul. 1999	Barton, et al.	378	84	
	AD	6,512,814	01-2003	Yokhin, et al.	378	82	
	AE	2001/0043668	11-2001	Hayashi, et al.	378	89	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
	AF						

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

CT	AG	Chihab et al., "New Apparatus for Grazing X-Ray Reflectometry in the Angle-Resolved Dispersive Mode", Journal of Applied Crystallography 22 (1989), p. 460.
	AH	XTF5011 Tube, Produced by Oxford Instruments of Scotts Valley, California. June 1999.
	AI	Doubly-Bent Focusing Crystal Optic, Produced by XOS Inc., of Albany, New York. July 2000.
	AJ	Wiener et al., "Characterization of Titanium Nitride Layers by Grazing-Emission X-Ray Fluorescence Spectrometry", in Applied Surface Science 125 (1998), p. 129.
	AK	Model S7032-0908N array, Produced by Hamamatsu, of Hamamatsu City, Japan. May 2000.
EXAMINER: Courtney Thomas		DATE CONSIDERED: 08.22.05
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

FORM PTO-1449 (Colb)	ATTY DOCKET NO. 4350-4004	SERIAL NUMBER 10/702,413
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT Boris YOKHIN	EXAMINER (N/A)
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## U.S. PATENT DOCUMENTS

Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
CT	AA	2001/0028699	10-2001	Iwasaki	378	84	
	AB	6,381,303	04-2002	Vu, et al.	378	46	
	AC	6,389,102	05-2002	Mazor, et al.	378	89	
	AD	5,574,284	11-1996	Farr	250	370.06	
	AE	5,151,588	09-1992	Kiri, et al.	250	208.1	
	AF	4,725,963	02-1988	Taylor, et al.	702	40	

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## OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

CT	AH	J. Spear, "Metrology for low-k materials", Silknet Alliance, 2003.
	AI	J.R. Levine Parrill, et al, "GISAXS - Glancing Incidence Small Angle X-ray Scattering", Journal de Physique IV 3 (December 1993), pages 411-417.
	AK	Jaklevic, et al., "High Rate X-Ray Fluorescence Analysis by Pulsed Excitation", IEEE Transactions on Nuclear Science NS-19:3 (1972), pp. 392-395.
	AL	Jaklevic, et al., "Small X-Ray Tubes for Energy Dispersive Analysis Using Semiconductor Spectrometers", Advances in X-Ray Analysis 15 (1972), pp. 266-275.
	AM	Jaklevic, et al., "Energy Dispersive X-Ray Fluorescence Spectrometry Using Pulsed X-Ray Excitation", Advances in X-Ray Analysis 19 (1976).
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Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
CT	AA	6,512,814	01-2003	Yokhin, et al.	378	82	
CT	AB	4,989,226	01-1991	Woodbury, et al.	378	145	
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	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
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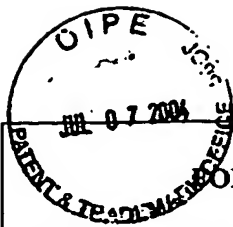
## OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

CT	AH	Wormington, Characterization of Pore Size Distribution in Low k Dielectrics Using X-ray Reflectivity", presented at the Sematech Gate Stack Engineering Workshop (Austin, Texas, May 2, 2002).
↓	AI	Ito, "X-ray Scattering Method for Determining Pore-Size Distribution in Low-k Thin Films", Presented at the International Sematech Ultra-Low-k Workshop (San Francisco, CA, June 6-7, 2002).
	AJ	N. Wu, et al, "Substepping and its Application to HST Imaging", 28-7-2003.
↓	AK	Holy et al., "High Resolution X-ray Scattering from Thin Films and Multilayers", Springer Verlag 1999, pp. 18-21.
	AL	
	AM	

EXAMINER: Courtney Thomas

DATE CONSIDERED: 08.22.05

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<b>FORM PTO-1449</b> <b>INFORMATION DISCLOSURE CITATION</b>	Attorney Docket: 4350-4004	Serial No.: 10/702,413
	Applicant: Boris YOKHIN	
	Filing Date: November 5, 2003	Group Art Unit: 2882

**U.S. PATENT DOCUMENTS**

Examiner Initial	Patent Number	Issue Date	Name	Class	Sub-Class	Filing Date
CT	6,744,950	06-2004	Aleksoff	385	48	08-2003
	6,643,354	11-2003	Koppel, et al.	378	86	04-2002
	6,507,634	01-2003	Koppel, et al.	378	54	02-2002
	6,453,006	09-2002	Koppel, et al.	378	86	03-2000
	2004/0052330	03-2004	Koppel, et al.	378	46	08-2003
	2002/0110218	08-2002	Koppel, et al.	378	86	04-2002
	2002/0097837	07-2002	Fanton, et al.	378	82	10-2001

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Patent Number	Publication Date	Country	Class	Sub-Class	Translation
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						<input type="checkbox"/> Yes <input type="checkbox"/> No
						<input type="checkbox"/> Yes <input type="checkbox"/> No

**OTHER DOCUMENTS (including Author, Title, Date, etc.)**


Examiner <i>Courtney Thomas</i>	Date Considered <i>08.22.05</i>
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